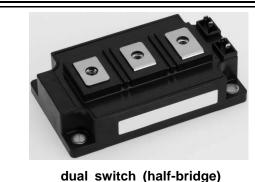


<IGBT Modules>

# CM600DY-24T

HIGH POWER SWITCHING USE INSULATED TYPE



Collector current I<sub>C</sub> ...... 6 0 0 A Collector-emitter voltage V<sub>CES</sub> ..... 1 2 0 0 V Maximum junction temperature T<sub>vjmax</sub> ...... 1 7 5 °C •Flat base type •Copper base plate (Nickel-plating) •Tin-plating signal terminals

**Dimension in mm** 

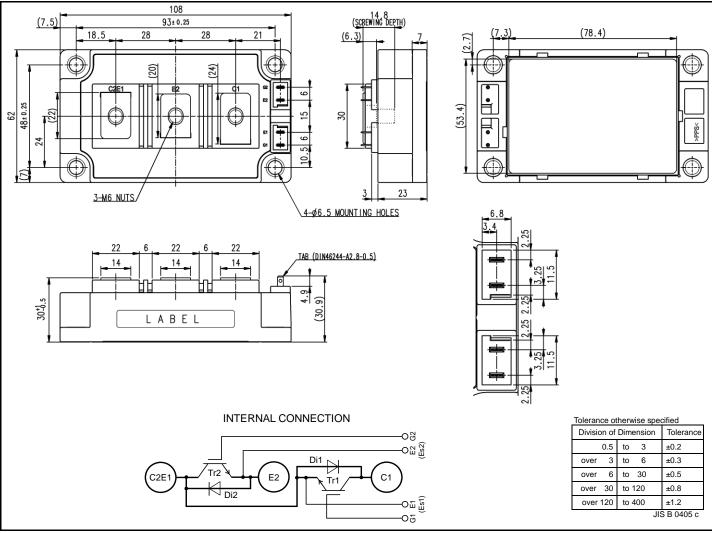
- RoHS Directive compliant
- •UL Recognized under UL1557, File No.E323585

#### APPLICATION

AC Motor Control, Motion/Servo Control, Power supply, etc.

- **OPTION** (Below options are available.)
  - •PC-TIM (Phase Change Thermal Interface Material) pre-apply
- $\bullet \mathsf{V}_{\mathsf{CEsat}}$  selection for parallel connection

#### **OUTLINE DRAWING & INTERNAL CONNECTION**



#### MAXIMUM RATINGS (Tvj=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1200	V	
$V_{\text{GES}}$	Gate-emitter voltage	C-E short-circuited	± 20	V	
lc		DC, T <sub>C</sub> =125 °C (Note2, 4)	600		
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	1200	— A	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	6250	W	
IE (Note1)		DC (Note2)	600		
IERM (Note1)	Emitter current	Pulse, Repetitive (Note3)	1200	A	
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T <sub>jmax</sub>	Maximum junction temperature	Instantaneous event (overload)	175	- °C	
T <sub>Cmax</sub>	Maximum case temperature (Note4)		125		
Tjop	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	- °C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +125		

#### ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Symbol	Itom	Item Conditions		Limits			Linit
Symbol	Item			Min.	Тур.	Max.	Unit
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited		-	-	1.0	mA
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	-	0.5	μA
V <sub>GE(th)</sub>	Gate-emitter threshold voltage	Ic=60 mA, VcE=10 V		5.4	6.0	6.6	V
		Ic=600 A, V <sub>GE</sub> =15 V,	T <sub>vj</sub> =25 °C	-	1.75	2.05	V
V <sub>CEsat</sub>		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	2.00	-	
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	2.10	-	
	Collector-emitter saturation voltage	I <sub>C</sub> =600 A,	T <sub>vj</sub> =25 °C	-	1.55	1.80	V
V <sub>CEsat</sub>		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	1.75	-	
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.80	-	
Cies	Input capacitance			-	-	123	
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited		-	-	3.6	nF
Cres	Reverse transfer capacitance			-	-	1.5	
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =600 V, I <sub>C</sub> =600 A, V <sub>GE</sub> =15 V		-	3.7	-	μC
t <sub>d(on)</sub>	Turn-on delay time	Vcc=600 V, Ic=600 A, VGE=±15 V,		-	-	500	- ns
t r	Rise time			-	-	200	
t <sub>d(off)</sub>	Turn-off delay time			-	-	600	
t <sub>f</sub>	Fall time	$-R_{G}=1.0 \Omega$ , Inductive load		-	-	300	1
	EC <sup>(Note.1)</sup> prminal) Emitter-collector voltage EC <sup>(Note.1)</sup> hip)	I <sub>E</sub> =600 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	1.85	2.25	
		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	2.00	-	V
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	2.00	-	
		I <sub>E</sub> =600 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	1.65	2.00	
			T <sub>vj</sub> =125 °C	-	1.65	-	V
(Cnip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.65	-	
t <sub>rr</sub> <sup>(Note1)</sup>	Reverse recovery time	$V_{CC}$ =600 V, I <sub>E</sub> =600 A, V <sub>GE</sub> =±15 V,		-	-	400	ns
Qrr (Note1)	Reverse recovery charge	$R_{G}$ =1.0 $\Omega$ , Inductive load		-	60	-	μC
Eon	Turn-on switching energy per pulse	$V_{CC}$ =600 V, $I_{C}$ = $I_{E}$ =600 A, $V_{GE}$ =±15 V, $R_{G}$ =1.0 $\Omega$ , $T_{vj}$ =150 °C,		-	56.6	-	
E <sub>off</sub>	Turn-off switching energy per pulse			-	64.3	-	mJ
Err (Note1)	Reverse recovery energy per pulse	Inductive load		-	38.2	-	mJ
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25 °C (Note4)		-	0.3	-	mΩ
r <sub>g</sub>	Internal gate resistance	Per switch		-	0.67	-	Ω

#### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions		Limits		
		Conditions	Min.	Тур.	Max.	Unit
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)	-	-	24	K/kW
R <sub>th(j-c)D</sub>	Thermai resistance	Junction to case, per Inverter FWD (Note4)	-	-	42	r./kvv
$R_{th(c-s)}$	Contact thermal resistance	Case to heat sink, Thermal grease applied (Note4,	5) _	13.3	-	K/kW
		per 1 module, PC-TIM applied (Note4, 7)	-	3.5	-	TVKVV

#### **MECHANICAL CHARACTERISTICS**

Symbol	Item	Conditions		Limits			Linit
				Min.	Тур.	Max.	Unit
Mt	Mounting torque	Main terminals	M 6 screw	3.5	4.0	4.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
ds	Creepage distance	Terminal to terminal		17.3	-	-	mm
		Terminal to base plate		25.3	-	-	
da	Clearance	Terminal to terminal		12.6	-	-	mm
		Terminal to base plate		21.8	-	-	
ec	Flatness of base plate	On the centerline X, Y (Note8)		±0	-	+200	μm
m	mass	-		-	260	-	g

\*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU. Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).

2. Junction temperature  $(T_{vj})$  should not increase beyond  $T_{vjmax}$  rating.

3. Pulse width and repetition rate should be such that the device junction temperature  $(T_{vj})$  dose not exceed  $T_{vjmax}$  rating.

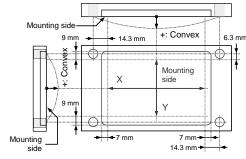
4. Case temperature (T<sub>c</sub>) and heat sink temperature (T<sub>s</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.

5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.

6. Typical value is measured by using thermally conductive grease of  $\lambda$ =0.9 W/(m·K)/D<sub>(C-S)</sub>=50 µm.

7. Typical value is measured by using PC-TIM of  $\lambda{=}3.4$  W/(m-K)/D<sub>(C-S)</sub>=50  $\mu m.$ 

8. The base plate (mounting side) flatness measurement points (X, Y) are shown in the following figure.



#### **RECOMMENDED OPERATING CONDITIONS**

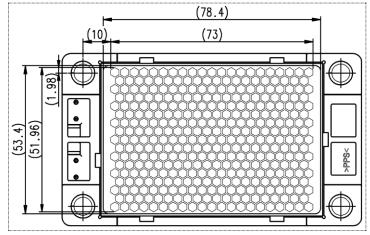
Symbol	Item	Conditions	Limits			Unit
	nem	Conditions	Min.	Тур.	Max.	Unit
V <sub>cc</sub>	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	850	V
$V_{\text{GEon}}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	1.0	-	10	Ω

#### CHIP LOCATION (Top view)

(108)(93) 50.4 δ œ 61.4 72.4 0 32. 21 Œ ÷ 44.87 44.8 DiazenTr2 Tr22 Di2 Tr2 C1 44.2 F (62) (48) E1 T<u>ul⊢D</u>∔ Tr1 18.7 17.9-<u>Tr1—D∔1</u>⊣ I + 0 ⊕ 0 Œ Œ 37.9-8 66.4 77.4 0 27 48. LABEL SIDE

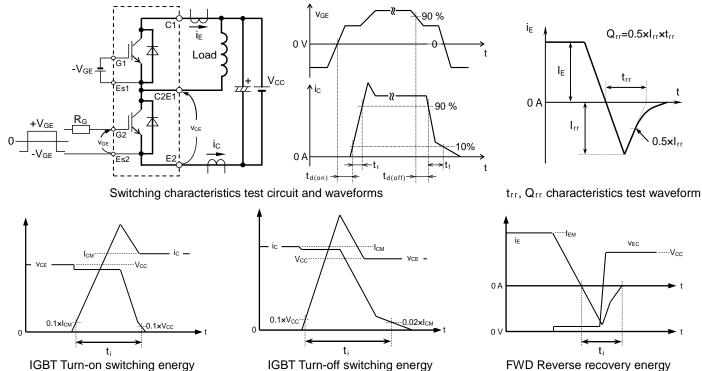
Tr1/Tr2: IGBT, Di1/Di2: FWD

Option: PC-TIM applied baseplate outline



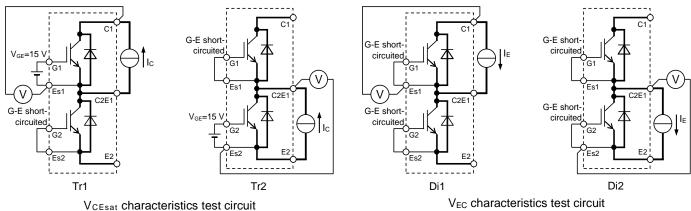
Dimension in mm, tolerance: ±1 mm

TEST CIRCUIT AND WAVEFORMS

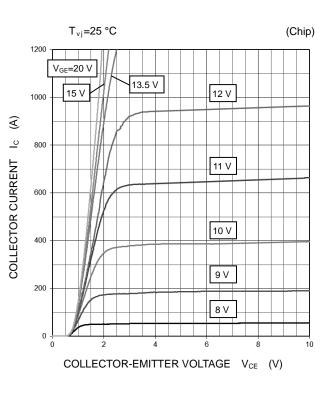


Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

#### **TEST CIRCUIT**

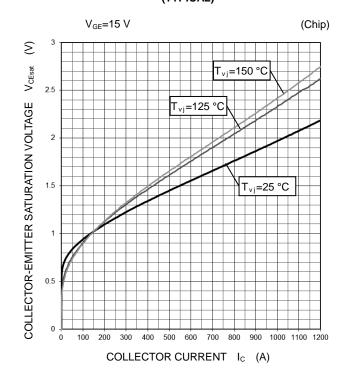


#### PERFORMANCE CURVES

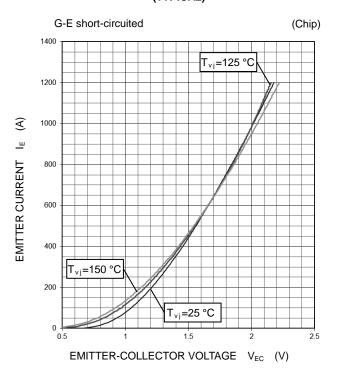


#### OUTPUT CHARACTERISTICS (TYPICAL)

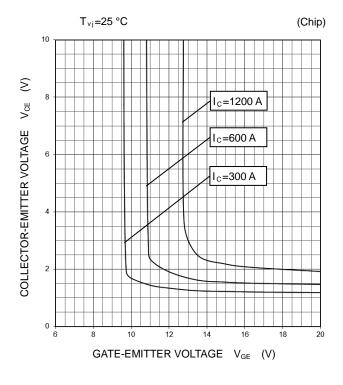
#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



#### FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)



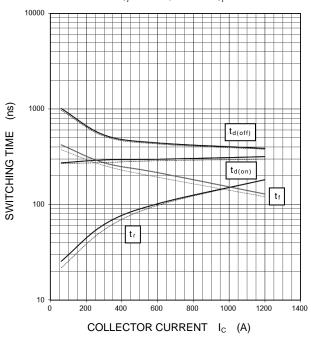




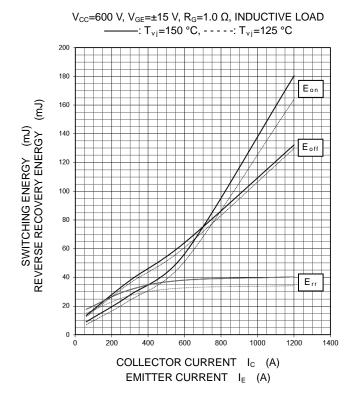
#### PERFORMANCE CURVES

HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

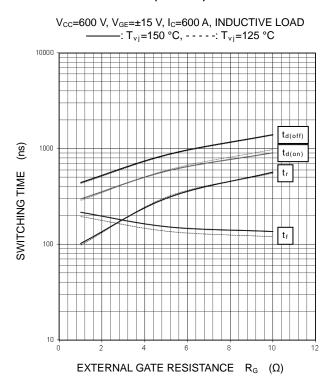
 $\begin{array}{c} V_{CC}{=}600 \ V, \ V_{GE}{=}{\pm}15 \ V, \ R_{G}{=}1.0 \ \Omega, \ \text{INDUCTIVE LOAD} \\ \hline \\ \hline \\ \hline \\ \hline \\ \end{array} \\ \begin{array}{c} T_{vj}{=}150 \ ^{\circ}\text{C}, \ -{---}{\cdot} \ T_{vj}{=}125 \ ^{\circ}\text{C} \end{array}$ 



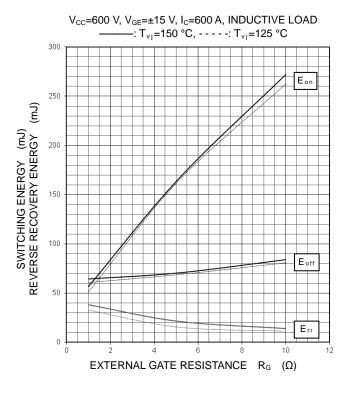
## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



#### HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

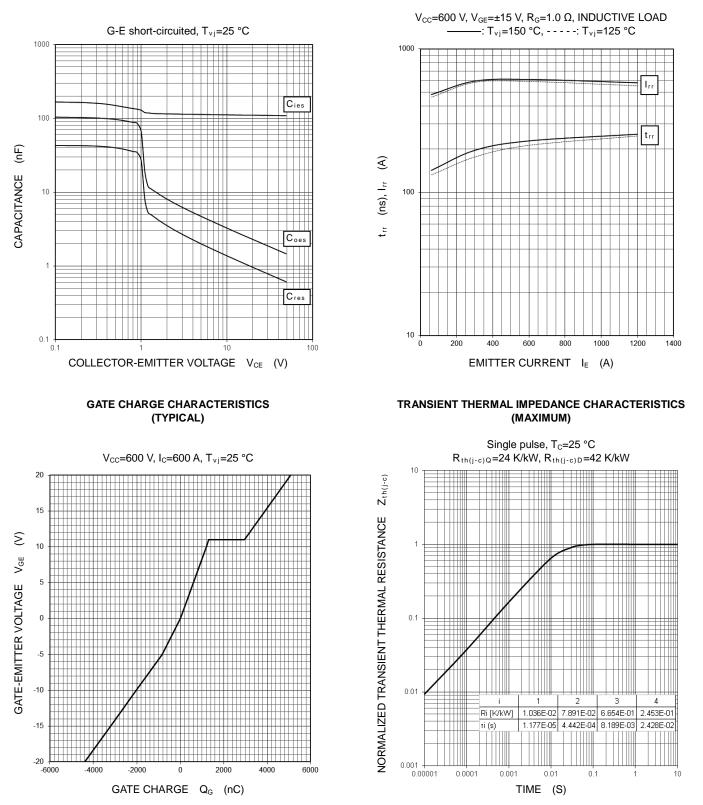


## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



#### PERFORMANCE CURVES





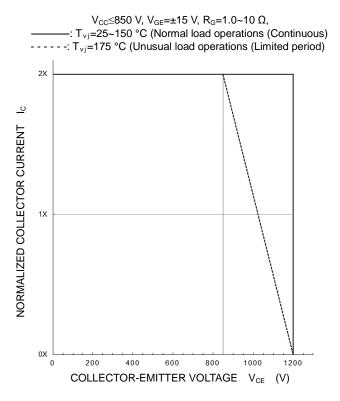
Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS

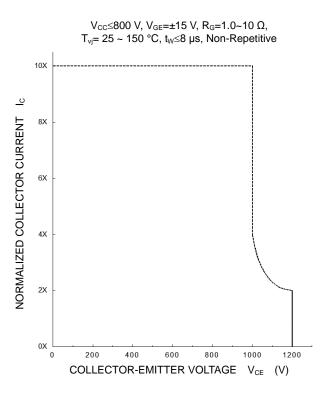
(TYPICAL)

#### PERFORMANCE CURVES

#### TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)



#### SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)



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